

**Notice of References Cited**

Application/Control No.

10/018,143

Applicant(s)/Patent Under  
Examination  
TKE ET AL

Examiner

William J. Klimowicz

Art Unit

2652

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,980,677 A	11-1999	Amo et al.	156/230
	B	US-6,066,218 A	05-2000	Kuhn et al.	156/87
	C	US-6,168,682 B1	01-2001	Bennett et al.	156/295
	D	US-6,200,402 B1	03-2001	Amo, Mikuni	156/235
	E	US-2003/0098131	05-2003	Hayasaka et al.	156/537
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 932149 A2	07-1999	European Patent	AMO, MIKUNI	G11B 07/26
	O	JP 04149839 A	05-1992	Japan	KUBO et al.	G11B 07/26
	P	JP 09063139 A	03-1997	Japan	NAKAMURA et al.	G11B 11/10
	Q	JP 09196709 A	07-1997	Japan	NAKAMURA et al.	G01D 15/32
	R	JP 10211669 A	08-1998	Japan	MATSUZAKI, MORIO	B32B 07/06
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.